Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/809,421	KIM, JIN KI
Examiner	Art Unit
Jung (John) H. Hur	2824

SEARCHED				
Class	Subclass	Date	Examiner	
365	49, 230.03	11/16/2006	JH	
711	108	11/16/2006	JH	
			-	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1			

SEAR (INCLUDING S	CH NOTES EARCH STRATEGY	)
	DATE	EXMR
EAST IEEE Google Scholar	11/16/2006	jh